

**Notice of References Cited**

Application/Control No.

09/763,365

Applicant(s)/Patent Under  
Reexamination  
TAKIZAWA ET AL.

Examiner

David L. Hogans

Art Unit

2813

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,124,614	09-2000	Ryum et al.	257/347
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	P					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Authc.; Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Quirk et al., Semiconductor Manufacturing Technology (2001), Prentice Hall, pages 309-311.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

U.S. Patent and Trademark Office  
PTO-892 (Rev. 01-2001)

**Notice of References Cited**

Part of Paper No. 25